Nano-textured Surfaces

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irradiate with 100-fs 10 kJ/m² pulses





'black silicon'

Appl. Phys. Lett. 73, 1673 (1998)









- maskless etching process
- self-organized, tall, sharp structures
- nanoscale structure on spikes

- Outlook
- Structural and chemical analysis
- **Properties**



reflectance (integrating sphere)



reflectance (integrating sphere)



transmittance (integrating sphere)



transmittance (integrating sphere)



absorptance (1 - R - T)



absorptance (1 - R - T)



Appl. Phys. Lett. 78, 1850 (2001)

- Points to keep in mind:
 - near unity absorption
 - sub-band gap absorption
 - IR photoelectron generation

- Points to keep in mind:
 - near unity absorption
 - sub-band gap absorption
 - IR photoelectron generation
 - high field emission at low fields





Outlook









cross-sectional TEM (F. Génin, M. Wall, LLNL)





cross-sectional TEM:

core of spikes: undisturbed Si

surface layer: disordered Si, impurities, nanocrystallites and pores













sulfur introduces states in the gap



sulfur introduces states in the gap



Janzén, et al., Phys. Rev. B 29,1907 (1984)

states broaden into a band



donor: metal-like behavior



acceptor: absorption until 3 µm



acceptor: absorption out to 3 µm



near-IR transmittance rises around 3 µm

Outlook

Structural and chemical analysis

- Properties

Outline











Outlook

development of spikes

- spike formation through grids
- cell adhesion
- functionalization



can ordering of spikes be improved by using a grid?







place grid in front of substrate



Outlook

scan laser beam





scan laser beam





remove grid



Si x2000 512 x 480 5kV 24mm H300.TIF - m402





Outlook



Microstructured silicon

fabricated by simple, maskless process



Microstructured silicon

fabricated by simple, maskless process

can be integrated with microelectronics



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